

EAST Search History**EAST Search History (Interference)**

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	6	427/255.28.cds. and (dummy or first or test) substrate and (second or bare) substrate and thick \$5	USPAT; UPAD	ADJ	ON	2009/07/21 16:04
L2	1	427/255.28.cds. and (measur\$5 adj3 thick \$5) and (set\$4 adj3 temperature)	USPAT; UPAD	ADJ	ON	2009/07/21 16:05
L3	106	"427".clas. and (measur\$5 adj3 thick \$5) and (set\$4 adj3 temperature)	USPAT; UPAD	ADJ	ON	2009/07/21 16:06
L4	37	((first or dummy or test) substrate and (second or bare) substrate and (measur\$5 adj3 thick \$5)).dm.	USPAT; UPAD	ADJ	ON	2009/07/21 16:08
L5	1	((first or dummy or test) substrate with oxide).dm. and (second substrate with (bare or silicon)).dm. and ((measur\$5 adj3 thick\$5) or (set\$4 adj3 temperature)).dm.	USPAT; UPAD	ADJ	ON	2009/07/21 16:12

7/ 21/ 2009 4:14:33 PM

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 \ 10\ 10523803.thermal processing multiple substrates.wsp